

Optimization of Wye-Delta-Type Quantum Hall Resistance Standard

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Abstract — Theoretically wye-delta transformation can be used to realize ultra-high resistances up to PΩ. For graphene-based quantum Hall array resistance standards fabricated to utilize the wye-delta transformation, a few challenges present themselves, including the unique quantized resistance in a graphene Hall bar and the limitation of the area of homogeneous high-quality graphene. In this paper, we discuss approaches to optimize the transformation for quantum Hall array resistance standard and propose a dual-output design for 1 MΩ and 100 MΩ as an alternative to other build-up techniques, shortening the path from quantum resistance standards.

Index Terms — dual-source bridge, wye-delta transformation, quantum Hall array resistance standard, dual-output.

I. INTRODUCTION

Wye-delta (or Y-Δ) transformation [1] is a well-known mathematical technique to simplify complex circuits, widely used in the analysis of three-phase electric power circuits. This technique attests the equivalence of a “Y”-shaped network (the orange schematic in Fig.1) and a “Δ”-shaped network (the green schematic in Fig.1) that connect the three terminals A, B, C. The “Y”-shaped network has an extra node in the center. The equivalence is manifested by the resistance values between each pair of the three terminals, as shown by equations (1-3).

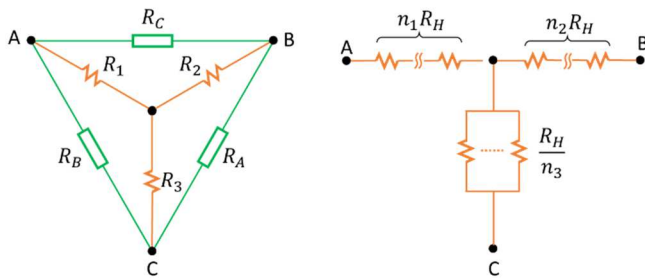


Fig. 1. (a) Schematic diagram for Y-Δ transformation. (b) Schematic diagram for quantum Hall array resistance standard based on Y-Δ transformation.

$$R_A = R_2 + R_3 + \frac{R_2 R_3}{R_1} \quad (1)$$

$$R_B = R_1 + R_3 + \frac{R_3 R_1}{R_2} \quad (2)$$

$$R_C = R_1 + R_2 + \frac{R_1 R_2}{R_3} \quad (3)$$

In the electrical calibration community, the transformation from Y-network to Δ-network is adopted to generate ultra-high resistance standard in the range of MΩ to PΩ [2-5]. As show by the equations (1-3), for large resistors, the resistance of the Δ-network is approximately proportional to the multiplication of the resistance of two arms in Y-network and inversely proportional to the resistance of the third arm. For example, $R_C = 10 \text{ M}\Omega$ can be realized by two $100 \text{ k}\Omega$ resistors (R_1, R_2) and one $1 \text{ k}\Omega$ resistor (R_3).

Recently, Y-Δ-type quantum Hall array resistance standard (QHARS) has been demonstrated by utilizing 79 graphene Hall bars to produce $R_C \approx 20.6 \text{ M}\Omega$ [5]. At 2.5 K and in a magnetic field above 4 T, the Hall resistance of each graphene Hall bar manifests $\nu = 2$ plateau ($R_H = R_K/2$), where $R_K = \frac{h}{e^2} = 25812.8074593 \dots \Omega$. In the previous proof-of-concept work, two arms of Y-network consist of 39 graphene Hall bars connected in series, respectively, and the third arm has a single graphene Hall bar. Measurement of R_C with a dual-source bridge shows a $5 \mu\Omega/\Omega$ offset from the theoretical value that has been attributed to non-ideal bridge ground connection and errors stemming from possible imperfect graphene Hall bars.

This work will present the analysis of various Y-network designs utilizing graphene Hall bars to produce $1 \text{ M}\Omega$, $10 \text{ M}\Omega$, and $100 \text{ M}\Omega$ resistors, which offers a preliminary approach to optimize ultra-high resistance QHARS.

II. WYE-DELTA-TYPE QHARS

To scale up the quantum Hall resistance using the Y-Δ transformation, we should choose series networks for arm 1 and arm 2 and a parallel network for arm 3 in the Y-configuration (Fig. 1b). For a symmetric Y-network, the resistances from the corresponding Δ-network are

$$R_A = R_B = \left(n_1 + \frac{2}{n_3} \right) R_H \quad (4)$$

$$R_C = (n_1^2 n_3 + 2n_1) R_H \quad (5)$$

For the nominal resistance value R_n and a chosen n_3 , we can solve equation (5) to obtain

$$n_1 = n_2 = \left(\frac{R_n}{n_3 R_H} + \frac{1}{n_3^2} \right)^{\frac{1}{2}} \quad (6)$$

Equation (6) is a useful tool to search for the optimized configuration (n_1, n_2, n_3) for a symmetric Y-network with

minimum difference (offset σ) between the nominal resistance R_n and the theoretical value R_C .

When adopting asymmetric Y-configuration for QHRS, equation (3) becomes

$$R_C = (n_1 n_2 n_3 + n_1 + n_2) R_H \quad (7)$$

Table 1.

| $R_n(\Omega)$ | n_1 | n_2 | n_3 | Total n | $R_1(\Omega)$ | $R_2(\Omega)$ | $R_3(\Omega)$ | $R_A(\Omega)$ | $R_B(\Omega)$ | $R_C(\Omega)$ | $\sigma/R_n (\mu\Omega/\Omega)$ |
|---------------|-------|-------|-------|-----------|---------------|---------------|---------------|---------------|---------------|---------------|---------------------------------|
| 1 000 000 | 1 | 1 | 75 | 77 | 12 906 | 12 906 | 172 | 13 251 | 13 251 | 993 793 | 6 207 |
| 1 000 000 | 3 | 3 | 8 | 14 | 38 719 | 38 719 | 1 613 | 41 946 | 41 946 | 1 006 699 | 6 699 |
| 1 000 000 | 25 | 2 | 1 | 28 | 322 660 | 25 813 | 12 906 | 39 752 | 496 897 | 993 793 | 6 207 |
| 10 000 000 | 6 | 6 | 21 | 33 | 77 438 | 77 438 | 615 | 78 668 | 78 668 | 9 912 118 | 8 788 |
| 10 000 000 | 1 | 86 | 8 | 95 | 12 906 | 1 109 951 | 1 613 | 1 250 308 | 14 538 | 10 002 463 | 246 |
| 100 000 000 | 31 | 31 | 8 | 70 | 400 099 | 400 099 | 1 613 | 403 325 | 403 325 | 100 024 629 | 246 |
| 100 000 000 | 6 | 158 | 8 | 172 | 77 438 | 2 039 212 | 1 613 | 2 083 309 | 79 113 | 99 998 816 | 12 |

Table 1 shows several Y-configurations for nominal resistance values of 1 M Ω , 10 M Ω , and 100 M Ω . For $R_n = 1$ M Ω , three Y-networks, $(n_1, n_2, n_3) = (1, 1, 75)$, $(3, 3, 8)$, $(25, 2, 1)$, yield similar offset $\sigma = |R_C - R_n|$ at the level of ≈ 6000 $\mu\Omega/\Omega$. Among these three configurations, only $(25, 2, 1)$ allows dual-source bridge triple-series connections to all quantum Hall resistance terminals, due to the single Hall bar in arm 3 [5]. However, $(3, 3, 8)$ is the best option for minimizing the fabrication error because it has the minimum number of Hall bar. For this configuration, arm 3 has much smaller resistance due to the parallel graphene Hall bars. We will demonstrate that this design can utilize the voltage sense capability of the two digital calibrators and a voltage detector in the dual-source bridge to eliminate the need for triple-series connections, because voltage detection has been found to be less sensitive to noise than current detection. For larger R_n , asymmetric Y-networks can also demonstrate improved precision, i.e., smaller σ .

Figure 2 shows a prototype of Y- Δ -type QHARS with dual-output of 1 M Ω and 100 M Ω , which can be realized by a total of 76 graphene Hall bar.

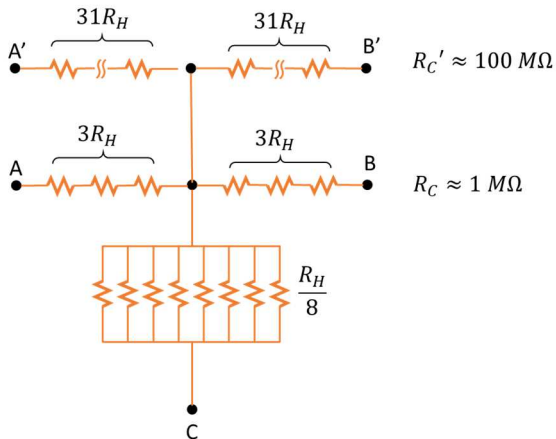


Figure 2. Schematic diagram of a Y- Δ -type QHARS with two outputs. The output resistance between terminals A and B is 1 M Ω . The output resistance between terminals A' and B' is 100 M Ω .

III. CONCLUSION

We applied analysis of the wye-delta transformation and compared several Y-network designs for QHARS with decade resistance values of 1 M Ω , 10 M Ω , and 100 M Ω . While symmetric Y-network shows advantages of utilizing less graphene Hall bars for a device and therefore reducing the fabrication complexity, an asymmetric design gives benefit of obtaining an output value R_C closer to a nominal resistance R_n , especially for higher R_n values. Following this work, we will fabricate and measure graphene QHARS with different Y-designs including the dual-output device shown in Figure 2.

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